

Colin Humphreys

List of Publications by Year in descending order

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317
papers

8,709
citations

38742
50
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62596
80
g-index

321
all docs

321
docs citations

321
times ranked

6660
citing authors

#	ARTICLE	IF	CITATIONS
1	Solid-State Lighting. MRS Bulletin, 2008, 33, 459-470.	3.5	303
2	Machine Learning Predicts Laboratory Earthquakes. Geophysical Research Letters, 2017, 44, 9276-9282.	4.0	272
3	Prospects of III-nitride optoelectronics grown on Si. Reports on Progress in Physics, 2013, 76, 106501.	20.1	249
4	Electron-beam-induced strain within InGa $\tilde{\text{N}}$ GaN quantum wells: False indium "cluster" detection in the transmission electron microscope. Applied Physics Letters, 2003, 83, 5419-5421.	3.3	248
5	Atom probe tomography today. Materials Today, 2007, 10, 36-42.	14.2	216
6	Optical and microstructural studies of InGa $\tilde{\text{N}}$ GaN single-quantum-well structures. Journal of Applied Physics, 2005, 97, 103508.	2.5	200
7	Carrier localization mechanisms in InGa $\tilde{\text{N}}$ GaN quantum wells. Applied Physics Letters, 2003, 82, 2755-2757.	3.2	165
8	Three-dimensional atom probe studies of an In $\tilde{\text{N}}$ GaN multiple quantum well structure: Assessment of possible indium clustering. Applied Physics Letters, 2007, 90, 061903.	3.3	160
9	Dopant profiling with the scanning electron microscope—A study of Si. Journal of Applied Physics, 2002, 91, 9116-9122.	2.5	133
10	Understanding x-ray diffraction of nonpolar gallium nitride films. Journal of Applied Physics, 2009, 105, .	2.5	128
11	Chemical mapping and formation of V-defects in InGa $\tilde{\text{N}}$ GaN multiple quantum wells. Applied Physics Letters, 2000, 77, 1274-1276.	3.3	126
12	Tunable optoelectronic and ferroelectric properties in Sc-based III-nitrides. Journal of Applied Physics, 2013, 114, .	2.5	124
13	Determination of the indium content and layer thicknesses in InGa $\tilde{\text{N}}$ GaN quantum wells by x-ray scattering. Journal of Applied Physics, 2003, 94, 1565-1574.	2.5	113
14	Threading dislocation reduction in (0001) GaN thin films using SiN $\tilde{\text{x}}$ interlayers. Journal of Crystal Growth, 2007, 300, 70-74.	1.5	111
15	Highlighting threading dislocations in MOVPE-grown GaN using an in situ treatment with SiH $\tilde{\text{4}}$ and NH $\tilde{\text{3}}$. Journal of Crystal Growth, 2006, 289, 506-514.	1.5	110
16	On the origin of threading dislocations in GaN films. Journal of Applied Physics, 2009, 106, .	2.5	108
17	Carrier leakage in InGa $\tilde{\text{N}}$ GaN quantum well light-emitting diodes emitting at 480 nm. Applied Physics Letters, 2003, 82, 2755-2757.	3.3	107
18	The consequences of high injected carrier densities on carrier localization and efficiency droop in InGa $\tilde{\text{N}}$ GaN quantum well structures. Journal of Applied Physics, 2012, 111, .	2.5	105

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19	Improvements in a-plane GaN crystal quality by a two-step growth process. Applied Physics Letters, 2008, 92, .	3.3	98
20	Equilibrium critical thickness for misfit dislocations in III-nitrides. Journal of Applied Physics, 2008, 104, .	2.5	94
21	Elastic constants and critical thicknesses of ScGaN and ScAlN. Journal of Applied Physics, 2013, 114, .	2.5	93
22	Characteristics and applications of micro-pixelated GaN-based light emitting diodes on Si substrates. Journal of Applied Physics, 2014, 115, .	2.5	92
23	Nanometer scale electron beam lithography in inorganic materials. Applied Physics Letters, 1984, 45, 1289-1291.	3.3	91
24	Does In form In-rich clusters in InGaN quantum wells?. Philosophical Magazine, 2007, 87, 1971-1982.	1.6	85
25	Accurate experimental determination of the Poisson's ratio of GaN using high-resolution x-ray diffraction. Journal of Applied Physics, 2007, 102, .	2.5	84
26	Electrophoretic manipulation of single DNA molecules in nanofabricated capillariesElectronic supplementary information (ESI) available: Four videoclips showing the movement of DNA molecules in nanocapillaries. See http://www.rsc.org/suppdata/lc/b3/b312592k/ . Lab on A Chip, 2004, 4, 225.	6.0	82
27	Three-dimensional atom probe analysis of green- and blue-emitting In _x Ga _{1-x} N/GaN multiple quantum well structures. Journal of Applied Physics, 2008, 104, .	2.5	82
28	Growth and characterisation of GaN with reduced dislocation density. Superlattices and Microstructures, 2004, 36, 393-401.	3.1	80
29	Microstructural origins of localization in InGaN quantum wells. Journal Physics D: Applied Physics, 2010, 43, 354003.	2.8	78
30	Morphological, structural, and emission characterization of trench defects in InGaN/GaN quantum well structures. Applied Physics Letters, 2012, 101, .	3.3	78
31	Electron beam writing on a 20-nm scale in metal-organic chemical vapour deposited Al ₂ O ₃ . Applied Physics Letters, 1983, 42, 392-394.	3.3	76
32	Role of gross well-width fluctuations in bright, green-emitting single InGaN/GaN quantum well structures. Applied Physics Letters, 2007, 90, 121911.	3.3	73
33	Dislocation reduction in gallium nitride films using scandium nitride interlayers. Applied Physics Letters, 2007, 91, .	3.3	72
34	Effect of growth interruptions on the light emission and indium clustering of InGaN/GaN multiple quantum wells. Applied Physics Letters, 2001, 79, 2594-2596.	3.3	68
35	The nature of carrier localisation in polar and nonpolar InGaN/GaN quantum wells. Journal of Applied Physics, 2016, 119, .	2.5	66
36	Electronic structure of GaN and In _x Ga _{1-x} N measured with electron energy-loss spectroscopy. Physical Review B, 2002, 66, .	3.2	63

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37	Novel fabrication method for nanometer-scale silicon dots and wires. Applied Physics Letters, 1993, 62, 1949-1951.	3.3	62
38	Structure and chemistry of the Si(111)/AlN interface. Applied Physics Letters, 2012, 100, .	3.3	61
39	The effects of Si doping on dislocation movement and tensile stress in GaN films. Journal of Applied Physics, 2011, 109, .	2.5	59
40	Effects of quantum well growth temperature on the recombination efficiency of InGaN/GaN multiple quantum wells that emit in the green and blue spectral regions. Applied Physics Letters, 2015, 107, .	3.3	58
41	Nanoscale-accuracy transfer printing of ultra-thin AlInGaN light-emitting diodes onto mechanically flexible substrates. Applied Physics Letters, 2013, 103, .	3.3	57
42	Structural, electronic, and optical properties of m -plane InGaN/GaN quantum wells: Insights from experiment and atomistic theory. Physical Review B, 2015, 92, .	3.2	57
43	Defect reduction in $(112\bar{2})$ semipolar GaN grown on m -plane sapphire using ScN interlayers. Applied Physics Letters, 2009, 94, .	3.3	54
44	The impact of trench defects in InGaN/GaN light emitting diodes and implications for the "green gap" problem. Applied Physics Letters, 2014, 105, .	3.3	54
45	Segregation of In to Dislocations in InGaN. Nano Letters, 2015, 15, 923-930.	9.1	54
46	Current-voltage instabilities in GaN/AlGaIn resonant tunnelling structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2003, 0, 2389-2392.	0.8	52
47	Scanning transmission electron microscopy investigation of the Si(111)/AlN interface grown by metalorganic vapor phase epitaxy. Applied Physics Letters, 2010, 97, .	3.3	52
48	Mg Doping Affects Dislocation Core Structures in GaN. Physical Review Letters, 2013, 111, 025502.	7.8	52
49	High resolution quantitative two-dimensional dopant mapping using energy-filtered secondary electron imaging. Journal of Applied Physics, 2006, 100, 054901.	2.5	51
50	Carrier distribution in InGaN/GaN tricolor multiple quantum well light emitting diodes. Applied Physics Letters, 2009, 95, .	3.3	51
51	Electron-beam-induced damage in amorphous SiO_2 and the direct fabrication of silicon nanostructures. Philosophical Magazine A: Physics of Condensed Matter, Structure, Defects and Mechanical Properties, 1998, 78, 491-506.	0.6	50
52	The impact of gross well width fluctuations on the efficiency of GaN-based light emitting diodes. Applied Physics Letters, 2013, 103, .	3.3	50
53	Nanometre hole formation in MgO using electron beams. Philosophical Magazine Letters, 1990, 61, 181-193.	1.2	49
54	Misfit dislocations in In-rich InGaIn/GaN quantum well structures. Physica Status Solidi (A) Applications and Materials Science, 2006, 203, 1729-1732.	1.8	48

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55	Microstructural evolution of nonpolar (11-20) GaN grown on (1-102) sapphire using a 3D-2D method. Journal of Applied Physics, 2009, 105, .	2.5	47
56	Atom probe tomography assessment of the impact of electron beam exposure on $\text{In}_x\text{Ga}_{1-x}\text{N}/\text{GaN}$ quantum wells. Applied Physics Letters, 2011, 99, .	3.3	47
57	A quantitative model for doping contrast in the scanning electron microscope using calculated potential distributions and Monte Carlo simulations. Journal of Applied Physics, 2011, 109, .	2.5	47
58	High-quality III-nitride films on conductive, transparent (2 $\bar{1}$...01)-oriented In^{2+} -Ga $_{2}\text{O}_3$ using a GaN buffer layer. Scientific Reports, 2016, 6, 29747.	3.3	46
59	Efficiency measurement of GaN-based quantum well and light-emitting diode structures grown on silicon substrates. Journal of Applied Physics, 2011, 109, .	2.5	45
60	The impact of electron beam damage on the detection of indium-rich localisation centres in InGa $_{1-x}\text{N}$ quantum wells using transmission electron microscopy. Journal of Materials Science, 2006, 41, 2729-2737.	3.7	44
61	The Spatial Distribution of Threading Dislocations in Gallium Nitride Films. Advanced Materials, 2009, 21, 3941-3944.	21.0	44
62	Carrier localization in the vicinity of dislocations in InGa $_{1-x}\text{N}$. Journal of Applied Physics, 2017, 121, .	2.5	44
63	Dislocation movement in GaN films. Applied Physics Letters, 2010, 97, .	3.3	43
64	Optimisation of GaN LEDs and the reduction of efficiency droop using active machine learning. Scientific Reports, 2016, 6, 24862.	3.3	43
65	Revealing all types of threading dislocations in GaN with improved contrast in a single plan view image. Applied Physics Letters, 2004, 85, 3411-3413.	3.3	41
66	GaN-based LEDs grown on 6-inch diameter Si (111) substrates by MOVPE. Proceedings of SPIE, 2009, , .	0.8	41
67	X-ray diffraction analysis of cubic zincblende III-nitrides. Journal Physics D: Applied Physics, 2017, 50, 433002.	2.8	41
68	X-ray topography of the coherency breakdown in $\text{Ge}_x\text{Si}_{1-x}/\text{Si}(100)$. Applied Physics Letters, 1988, 53, 2083-2085.	3.3	40
69	Structure and strain relaxation effects of defects in $\text{In}_x\text{Ga}_{1-x}\text{N}$ epilayers. Journal of Applied Physics, 2014, 116, .	2.5	38
70	Comment on "AlN/GaN double-barrier resonant tunneling diodes grown by rf-plasma-assisted molecular-beam epitaxy" [Appl. Phys. Lett. 81, 1729 (2002)]. Applied Physics Letters, 2003, 83, 3626-3627.	3.3	37
71	Mechanical properties of graphene. Applied Physics Reviews, 2021, 8, .	11.3	37
72	Electronic and optical properties of nonpolar a-plane GaN quantum wells. Physical Review B, 2010, 82, .	3.2	36

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73	Towards predictive modeling of near-edge structures in electron energy-loss spectra of AlN-based ternary alloys. Physical Review B, 2011, 83, .	3.2	36
74	The significance of Bragg's law in electron diffraction and microscopy, and Bragg's second law. Acta Crystallographica Section A: Foundations and Advances, 2013, 69, 45-50.	0.3	36
75	Electrons seen in orbit. Nature, 1999, 401, 21-22.	27.8	35
76	The dissociation of the [111] dislocation in GaN. Philosophical Magazine, 2013, 93, 3925-3938.	1.6	35
77	3D Strain in 2D Materials: To What Extent is Monolayer Graphene Graphite?. Physical Review Letters, 2019, 123, 135501.	7.8	35
78	Optical properties of GaN/AlGaIn quantum wells grown on nonpolar substrates. Applied Physics Letters, 2008, 93, 101901.	3.3	34
79	Correlations between the morphology and emission properties of trench defects in InGaIn/GaN quantum wells. Journal of Applied Physics, 2013, 113, .	2.5	34
80	The effect of dislocations on the efficiency of InGaIn/GaN solar cells. Solar Energy Materials and Solar Cells, 2013, 117, 279-284.	6.2	34
81	Nanocathodoluminescence Reveals Mitigation of the Stark Shift in InGaIn Quantum Wells by Si Doping. Nano Letters, 2015, 15, 7639-7643.	9.1	33
82	Characterization of InGaIn quantum wells with gross fluctuations in width. Journal of Applied Physics, 2007, 102, .	2.5	31
83	Analysis of InGaIn/GaN single quantum wells by X-ray scattering and transmission electron microscopy. Physica Status Solidi (B): Basic Research, 2003, 240, 297-300.	1.5	30
84	High excitation carrier density recombination dynamics of InGaIn/GaN quantum well structures: Possible relevance to efficiency droop. Applied Physics Letters, 2013, 102, 022106.	3.3	29
85	Correlating electroluminescence characterization and physics-based models of InGaIn/GaN LEDs: Pitfalls and open issues. AIP Advances, 2014, 4, .	1.3	29
86	Dislocations in AlGaIn: Core Structure, Atom Segregation, and Optical Properties. Nano Letters, 2017, 17, 4846-4852.	9.1	29
87	Electron-beam induced crystallization transition in self-developing amorphous AlF3 resists. Applied Physics Letters, 1996, 69, 170-172.	3.3	28
88	Degradation of InGaIn-GaN laser diodes analyzed by microphotoluminescence and microelectroluminescence mappings. Applied Physics Letters, 2008, 92, 151110.	3.3	28
89	Temperature and Bias Dependent Trap Capture Cross Section in AlGaIn/GaN HEMT on 6-in Silicon With Carbon-Doped Buffer. IEEE Transactions on Electron Devices, 2017, 64, 4868-4874.	3.0	28
90	The ABC model of recombination reinterpreted: Impact on understanding carrier transport and efficiency droop in InGaIn/GaN light emitting diodes. Journal of Applied Physics, 2017, 122, 234505.	2.5	28

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91	Vertical leakage mechanism in GaN on Si high electron mobility transistor buffer layers. Journal of Applied Physics, 2018, 124, .	2.5	28
92	Imaging dislocation cores “ the way forward. Philosophical Magazine, 2006, 86, 4781-4796.	1.6	27
93	Coincident Electron Channeling and Cathodoluminescence Studies of Threading Dislocations in GaN. Microscopy and Microanalysis, 2014, 20, 55-60.	0.4	27
94	What is red? On the chromaticity of orange-red InGaN/GaN based LEDs. Journal of Applied Physics, 2018, 124, .	2.5	27
95	Insights into the origin of threading dislocations in GaN/Al ₂ O ₃ from atomic force microscopy. Applied Physics Letters, 2006, 89, 011914.	3.3	26
96	Dielectric response of wurtzite gallium nitride in the terahertz frequency range. Solid State Communications, 2016, 247, 68-71.	1.9	26
97	Structural and Optical Emission Uniformity of m-Plane InGaN Single Quantum Wells in Core-Shell Nanorods. Crystal Growth and Design, 2016, 16, 1907-1916.	3.0	26
98	Structural properties of wurtzitelike ScGaN films grown by NH ₃ -molecular beam epitaxy. Journal of Applied Physics, 2009, 106, 113533.	2.5	25
99	Direct Observation of Depth-Dependent Atomic Displacements Associated with Dislocations in Gallium Nitride. Physical Review Letters, 2014, 113, 135503.	7.8	25
100	Solution-Processed Epitaxial Growth of Arbitrary Surface Nanopatterns on Hybrid Perovskite Monocrystalline Thin Films. ACS Nano, 2020, 14, 11029-11039.	14.6	25
101	Optical polarization anisotropy of a-plane GaN/AlGaIn multiple quantum well structures grown on r-plane sapphire substrates. Journal of Applied Physics, 2009, 105, 123112.	2.5	24
102	The atomic structure of polar and non-polar InGaIn quantum wells and the green gap problem. Ultramicroscopy, 2017, 176, 93-98.	1.9	24
103	The effect of growth condition on the structure of 2H “ AlN films deposited on Si(111) by plasma-assisted molecular beam epitaxy. Journal of Materials Research, 1999, 14, 2036-2042.	2.6	23
104	Determination of relative internal quantum efficiency in InGaIn/GaN quantum wells. Journal of Applied Physics, 2005, 98, 053509.	2.5	22
105	The effect of wafer curvature on x-ray rocking curves from gallium nitride films. Journal of Applied Physics, 2008, 103, .	2.5	22
106	The microstructure of non-polar a-plane (112̄0) InGaIn quantum wells. Journal of Applied Physics, 2016, 119, .	2.5	22
107	Effects of KOH etching on the properties of Ga-polar n-GaN surfaces. Philosophical Magazine, 2006, 86, 2315-2327.	1.6	21
108	Low temperature photoluminescence and cathodoluminescence studies of nonpolar GaN grown using epitaxial lateral overgrowth. Journal of Applied Physics, 2010, 108, 033523.	2.5	21

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109	Structural impact on the nanoscale optical properties of InGaN core-shell nanorods. Applied Physics Letters, 2017, 110, .	3.3	21
110	High resolution transmission electron microscopy and three-dimensional atom probe microscopy as complementary techniques for the high spatial resolution analysis of GaN based quantum well systems. Materials Science and Technology, 2008, 24, 675-681.	1.6	20
111	The effects of Si-doped prelayers on the optical properties of InGaN/GaN single quantum well structures. Applied Physics Letters, 2014, 105, .	3.3	20
112	Effect of growth temperature and V/III-ratio on the surface morphology of MOVPE-grown cubic zincblende GaN. Journal of Applied Physics, 2018, 124, .	2.5	20
113	Mapping the potential within a nanoscale undoped GaAs region using a scanning electron microscope. Applied Physics Letters, 2004, 84, 2109-2111.	3.3	19
114	The origin and reduction of dislocations in Gallium Nitride. Journal of Materials Science: Materials in Electronics, 2008, 19, 208-214.	2.2	19
115	Assessment of the performance of scanning capacitance microscopy for n-type gallium nitride. Journal of Vacuum Science & Technology B, 2008, 26, 611-617.	1.3	19
116	Defect reduction in non-polar (11 $\bar{2}$ 0) GaN grown on (1 $\bar{1}$ 02) sapphire. Physica Status Solidi (A) Applications and Materials Science, 2009, 206, 1190-1193.	1.8	19
117	InGaN/GaN LEDs grown on Si(111): dependence of device performance on threading dislocation density and emission wavelength. Physica Status Solidi C: Current Topics in Solid State Physics, 2010, 7, 2168-2170.	0.8	19
118	Optimizing GaN () heteroepitaxial templates grown on () sapphire. Physica Status Solidi (B): Basic Research, 2016, 253, 61-66.	1.5	19
119	Atomic Arrangement of a Z-Shape Faulted Dipole within Deformed GaAs. Physical Review Letters, 1998, 81, 5350-5353.	7.8	18
120	Growth of non-polar (11-20) InGaN quantum dots by metal organic vapour phase epitaxy using a two temperature method. APL Materials, 2014, 2, .	5.1	18
121	Enhancement mode operation in AlInN/GaN (MIS)HEMTs on Si substrates using a fluorine implant. Semiconductor Science and Technology, 2015, 30, 105007.	2.0	18
122	Comparative studies of efficiency droop in polar and non-polar InGaN quantum wells. Applied Physics Letters, 2016, 108, .	3.3	18
123	InGaN as a Substrate for AC Photoelectrochemical Imaging. Sensors, 2019, 19, 4386.	3.8	18
124	Exciton localization in InGaN/GaN single quantum well structures. Physica Status Solidi (B): Basic Research, 2003, 240, 344-347.	1.5	17
125	Highly conductive modulation doped composition graded p-AlGaN/(AlN)/GaN multiheterostructures grown by metalorganic vapor phase epitaxy. Journal of Applied Physics, 2009, 106, .	2.5	17
126	Low temperature carrier redistribution dynamics in InGaN/GaN quantum wells. Journal of Applied Physics, 2014, 115, .	2.5	17

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127	Dislocation-related trap levels in nitride-based light emitting diodes. Applied Physics Letters, 2014, 104, .	3.3	17
128	Control of threshold voltage in E-mode and D-mode GaN-on-Si metal-insulator-semiconductor heterostructure field effect transistors by <i>in-situ</i> fluorine doping of atomic layer deposition Al ₂ O ₃ gate dielectrics. Applied Physics Letters, 2016, 108, .	3.3	17
129	Effect of humidity on the interlayer interaction of bilayer graphene. Physical Review B, 2019, 99, .	3.2	17
130	Electron energy loss spectroscopy studies of the amorphous to crystalline transition in FeF ₃ . Journal of Applied Physics, 1999, 86, 2499-2504.	2.5	16
131	Resonant excitation photoluminescence studies of InGaN ⁺ GaN single quantum well structures. Applied Physics Letters, 2006, 89, 211901.	3.3	16
132	Practical issues in carrier-contrast imaging of GaN structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2007, 4, 2576-2580.	0.8	16
133	Scanning capacitance microscopy studies of unintentional doping in epitaxial lateral overgrowth GaN. Journal of Applied Physics, 2009, 106, .	2.5	16
134	Low dislocation density nonpolar (11 $\bar{2}$ 0) GaN films achieved using scandium nitride interlayers. Physica Status Solidi C: Current Topics in Solid State Physics, 2010, 7, 1778-1780.	0.8	16
135	Study of efficiency droop and carrier localisation in an InGaN/GaN quantum well structure. Physica Status Solidi C: Current Topics in Solid State Physics, 2011, 8, 2194-2196.	0.8	16
136	A study of the inclusion of prelayers in InGaN/GaN single \bar{c} - and multiple \bar{c} -quantum \bar{c} -well structures. Physica Status Solidi (B): Basic Research, 2015, 252, 866-872.	1.5	16
137	Dislocation core structures in (0001) InGaN. Journal of Applied Physics, 2016, 119, .	2.5	16
138	Investigation of indium gallium nitride facet-dependent nonpolar growth rates and composition for core \bar{c} -shell light-emitting diodes. Journal of Nanophotonics, 2016, 10, 016010.	1.0	16
139	All-GaN-Integrated Cascode Heterojunction Field Effect Transistors. IEEE Transactions on Power Electronics, 2017, 32, 8743-8750.	7.9	16
140	Photoluminescence studies of cubic GaN epilayers. Physica Status Solidi (B): Basic Research, 2017, 254, 1600733.	1.5	16
141	Optical and microstructural properties of semi-polar (11-22) InGaN/GaN quantum well structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2009, 6, S727-S730.	0.8	15
142	Determination of the composition and thickness of semi-polar and non-polar III-nitride films and quantum wells using X-ray scattering. Journal of Applied Physics, 2012, 111, .	2.5	15
143	Growth, microstructure and morphology of epitaxial ScGa ₂ N films. Physica Status Solidi (A) Applications and Materials Science, 2012, 209, 33-40.	1.8	15
144	Properties of trench defects in InGaN/GaN quantum well structures. Physica Status Solidi (A) Applications and Materials Science, 2013, 210, 195-198.	1.8	15

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145	Dislocation core structures in Si-doped GaN. Applied Physics Letters, 2015, 107, .	3.3	15
146	Investigation of unintentional indium incorporation into GaN barriers of InGaN/GaN quantum well structures. Physica Status Solidi (B): Basic Research, 2015, 252, 928-935.	1.5	15
147	Growth and coalescence studies of oriented GaN on pre-structured sapphire substrates using marker layers. Physica Status Solidi (B): Basic Research, 2016, 253, 46-53.	1.5	15
148	Comparative study of sputtered and spin-coatable aluminum oxide electron beam resists. Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena, 2000, 18, 2737.	1.6	14
149	Electrically driven single InGaN/GaN quantum dot emission. Applied Physics Letters, 2008, 93, .	3.3	14
150	Carrier Density Dependent Localization and Consequences for Efficiency Droop in InGaN/GaN Quantum Well Structures. Japanese Journal of Applied Physics, 2013, 52, 08JK10.	1.5	14
151	Optical studies of non-polar ($\bar{1}11$) InGaN/GaN multi-quantum wells grown on freestanding bulk GaN. Physica Status Solidi (B): Basic Research, 2015, 252, 965-970.	1.5	14
152	Determination of axial and lateral exciton diffusion length in GaN by electron energy dependent cathodoluminescence. Journal of Applied Physics, 2016, 120, .	2.5	14
153	Solid-State Lighting Based on Light Emitting Diode Technology. , 2016, , 87-118.		14
154	Microtwin nucleation and propagation in heteroepitaxial II-VI compounds on (001)-oriented GaAs substrates. Philosophical Magazine A: Physics of Condensed Matter, Structure, Defects and Mechanical Properties, 1995, 72, 39-57.	0.6	13
155	Mechanisms of bending of threading dislocations in MOVPE-grown GaN on (0001) sapphire. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 1750-1753.	0.8	13
156	Morphological study of non-polar ($11\bar{2}0$) GaN grown on r -plane ($1\bar{1}02$) sapphire. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 1786-1788.	0.8	13
157	Atom probe tomography characterisation of a laser diode structure grown by molecular beam epitaxy. Journal of Applied Physics, 2012, 111, 053508.	2.5	13
158	Composition and luminescence studies of InGaN epilayers grown at different hydrogen flow rates. Semiconductor Science and Technology, 2013, 28, 065011.	2.0	13
159	A comparison of the optical properties of InGaN/GaN multiple quantum well structures grown with and without Si-doped InGaN prelayers. Journal of Applied Physics, 2016, 119, .	2.5	13
160	Mechanisms preventing trench defect formation in InGaN/GaN quantum well structures using hydrogen during GaN barrier growth. Physica Status Solidi (B): Basic Research, 2017, 254, 1600666.	1.5	13
161	Recombination from polar InGaN/GaN quantum well structures at high excitation carrier densities. Physical Review B, 2018, 98, .	3.2	13
162	TEM and PL characterisation of MBE-grown epitaxial GaN/GaAs. Materials Research Society Symposia Proceedings, 1996, 423, 311.	0.1	12

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163	High quantum efficiency InGaN/GaN structures emitting at 540 nm. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 1970-1973.	0.8	12
164	High photoluminescence quantum efficiency InGaN multiple quantum well structures emitting at 380nm. Journal of Applied Physics, 2007, 101, 033516.	2.5	12
165	Very low dislocation density, resistive GaN films obtained using transition metal nitride interlayers. Physica Status Solidi (A) Applications and Materials Science, 2008, 205, 1064-1066.	1.8	12
166	Atom probe reveals the structure of In _x Ga _{1-x} N based quantum wells in three dimensions. Physica Status Solidi (B): Basic Research, 2008, 245, 861-867.	1.5	12
167	Coherent terahertz acoustic vibrations in polar and semipolar gallium nitride-based superlattices. Applied Physics Letters, 2009, 94, 011909.	3.3	12
168	A transmission electron microscopy study of microstructure evolution with increasing anneal temperature in Ti/Al ohmic contacts to n-GaN. Journal of Electronic Materials, 2001, 30, L13-L16.	2.2	11
169	A comparative study of near-UV emitting InGaN quantum wells with AlGaIn and AlInGaIn barriers. Physica Status Solidi (A) Applications and Materials Science, 2006, 203, 1819-1823.	1.8	11
170	High-efficiency InGaN/GaN quantum well structures on large area silicon substrates. Physica Status Solidi (A) Applications and Materials Science, 2012, 209, 13-16.	1.8	11
171	Polarized photoluminescence excitation spectroscopy of a-plane InGaN/GaN multiple quantum wells grown on r-plane sapphire. Journal of Applied Physics, 2014, 115, 113106.	2.5	11
172	Optical and structural properties of dislocations in InGaN. Journal of Applied Physics, 2019, 125, .	2.5	11
173	Wafer-scale Graphene Anodes Replace Indium Tin Oxide in Organic Light-Emitting Diodes. Advanced Optical Materials, 2022, 10, 2101675.	7.3	11
174	Quantifying The Effects Of Amorphous Layers on Image Contrast Using Energy Filtered Transmission Electron Microscopy. Materials Research Society Symposia Proceedings, 1994, 354, 495.	0.1	10
175	Detection of random alloy fluctuations in high-resolution transmission electron micrographs of AlGaAs. Philosophical Magazine A: Physics of Condensed Matter, Structure, Defects and Mechanical Properties, 1995, 72, 1015-1030.	0.6	10
176	Identification of interfacial layers in Ohmic contacts to n-type GaN and Al _x Ga _{1-x} N/GaN heterostructures using high-resolution electron microscopy. The Philosophical Magazine: Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties, 2001, 81, 1725-1744.	0.6	10
177	Electric fields in AlGaIn/GaN quantum well structures. Physica Status Solidi (B): Basic Research, 2006, 243, 1551-1559.	1.5	10
178	Effects of an InGaN prelayer on the properties of InGaN/GaN quantum well structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2014, 11, 710-713.	0.8	10
179	The effects of varying threading dislocation density on the optical properties of InGaN/GaN quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2014, 11, 750-753.	0.8	10
180	Enhancement-mode metal-insulator-semiconductor GaN/AlInN/GaN heterostructure field-effect transistors on Si with a threshold voltage of +3.0 V and blocking voltage above 1000 V. Applied Physics Express, 2015, 8, 036502.	2.4	10

#	ARTICLE	IF	CITATIONS
181	Nano-cathodoluminescence reveals the effect of electron damage on the optical properties of nitride optoelectronics and the damage threshold. Journal of Applied Physics, 2016, 120, 165704.	2.5	10
182	Evolution of the m -Plane Quantum Well Morphology and Composition within a GaN/InGaN Core-Shell Structure. Crystal Growth and Design, 2017, 17, 474-482.	3.0	10
183	Effect of stacking faults on the photoluminescence spectrum of zincblende GaN. Journal of Applied Physics, 2018, 123, .	2.5	10
184	Famines and cataclysmic volcanism. Geology Today, 1994, 10, 181-185.	0.9	9
185	Characterization of Ultrathin Doping Layers in Semiconductors. Microscopy and Microanalysis, 1997, 3, 352-363.	0.4	9
186	GaN-InGaN Quantum Well and LED Structures Grown in a Close Coupled Showerhead (CCS) MOCVD Reactor. Physica Status Solidi A, 2002, 192, 354-359.	1.7	9
187	Morphological changes of InGaN epilayers during annealing assessed by spectral analysis of atomic force microscopy images. Journal of Applied Physics, 2009, 106, 054319.	2.5	9
188	The impact of growth parameters on trench defects in InGaN/GaN quantum wells. Physica Status Solidi (A) Applications and Materials Science, 2014, 211, 740-743.	1.8	9
189	Local carrier recombination and associated dynamics in m -plane InGaN/GaN quantum wells probed by picosecond cathodoluminescence. Applied Physics Letters, 2016, 109, .	3.3	9
190	Automatized convergence of optoelectronic simulations using active machine learning. Applied Physics Letters, 2017, 111, .	3.3	9
191	On the dissociation of prism plane superdislocations in Ti_3Al . Philosophical Magazine Letters, 1995, 72, 393-403.	1.2	8
192	Interfacial reaction and defect microstructure of epitaxial MnSb/Si(111) grown by hot-wall epitaxy. Journal of Applied Physics, 1998, 83, 5504-5508.	2.5	8
193	Study of sample thickness dependence in electron-beam irradiation of self-developing inorganic materials. Journal of Applied Physics, 1999, 85, 148-152.	2.5	8
194	Response to "Comment on "Three-dimensional atom probe studies of an $\text{In}_x\text{Ga}_{1-x}\text{N}$ -GaN multiple quantum well structure: assessment of possible indium clustering" [Appl. Phys. Lett. 91, 176101 (2007)]. Applied Physics Letters, 2007, 91, 176102.	3.3	8
195	The effects of annealing on non-polar $(1\ 1\ 2\ \bar{0})$ a-plane GaN films. Journal of Crystal Growth, 2010, 312, 3536-3543.	1.5	8
196	Electron holography of an in-situ biased GaN-based LED. Physica Status Solidi C: Current Topics in Solid State Physics, 2012, 9, 704-707.	0.8	8
197	SCM and SIMS investigations of unintentional doping in III-nitrides. Physica Status Solidi C: Current Topics in Solid State Physics, 2015, 12, 403-407.	0.8	8
198	Effect of the barrier growth mode on the luminescence and conductivity micron scale uniformity of InGaN light emitting diodes. Journal of Applied Physics, 2015, 117, 115705.	2.5	8

#	ARTICLE	IF	CITATIONS
199	n-Type conductivity bound by the growth temperature: the case of $\text{Al}_{0.72}\text{Ga}_{0.28}\text{N}$ highly doped by silicon. Journal of Materials Chemistry C, 2016, 4, 8291-8296.	5.5	8
200	Chemical mapping of InGaN MQWs. Journal of Crystal Growth, 2001, 230, 438-441.	1.5	7
201	Dislocation reduction in GaN grown on Si(111) using a strain-driven 3D GaN interlayer. Physica Status Solidi (B): Basic Research, 2010, 247, 1753-1756.	1.5	7
202	Inclined dislocation arrays in AlGaIn/AlGaIn quantum well structures emitting at 290 nm. Journal of Applied Physics, 2010, 108, 123522.	2.5	7
203	The impact of substrate miscut on the morphology of InGaIn epitaxial layers subjected to a growth interruption. Journal of Applied Physics, 2013, 113, 063503.	2.5	7
204	Theoretical and experimental analysis of the photoluminescence and photoluminescence excitation spectroscopy spectra of m -plane InGaIn/GaN quantum wells. Applied Physics Letters, 2016, 109, .	3.3	7
205	Room temperature PL efficiency of InGaIn/GaN quantum well structures with prelayers as a function of number of quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2016, 13, 248-251.	0.8	7
206	Structural and magnetic properties of ultra-thin Fe films on metal-organic chemical vapour deposited GaN(0001). Journal of Applied Physics, 2017, 121, .	2.5	7
207	Effect of Size on the Luminescent Efficiency of Perovskite Nanocrystals. ACS Applied Energy Materials, 2019, 2, 6998-7004.	5.1	7
208	Unexpected softness of bilayer graphene and softening of A-A stacked graphene layers. Physical Review B, 2020, 101, .	3.2	7
209	Scanning transmission electron beam induced conductivity investigation of a $\text{Si}/\text{Si}_{1-x}\text{Ge}_x/\text{Si}$ heterostructure. Journal of Applied Physics, 1996, 80, 2527-2529.	2.5	6
210	Effects of oxygen plasma treatment on the formation of ohmic contacts to GaN and AlGaIn. Physica Status Solidi (B): Basic Research, 2004, 241, 2820-2824.	1.5	6
211	Degradation of InGaN laser diodes grown by molecular beam epitaxy. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 2204-2206.	0.8	6
212	Measurement of the Al content in AlGaIn epitaxial layers by combined energy-dispersive X-ray and electron energy-loss spectroscopy in a transmission electron microscope. Physica Status Solidi C: Current Topics in Solid State Physics, 2012, 9, 1079-1082.	0.8	6
213	Carrier distributions in InGaIn/GaN light-emitting diodes. Physica Status Solidi (B): Basic Research, 2015, 252, 890-894.	1.5	6
214	Effects of a Si-doped InGaIn Underlayer on the Optical Properties of InGaIn/GaN Quantum Well Structures with Different Numbers of Quantum Wells. Materials, 2018, 11, 1736.	2.9	6
215	Photomodulated Reflectivity Measurement of Free-Carrier Dynamics in InGaIn/GaN Quantum Wells. ACS Photonics, 2018, 5, 4437-4446.	6.6	6
216	Effects of surface plasma treatment on threshold voltage hysteresis and instability in metal-insulator-semiconductor (MIS) AlGaIn/GaN heterostructure HEMTs. Journal of Applied Physics, 2018, 123, .	2.5	6

#	ARTICLE	IF	CITATIONS
217	Nanomechanics of graphene oxide-bacteriophage based self-assembled porous composites. Scientific Reports, 2020, 10, 15618.	3.3	6
218	Growth of GaN films on (0 0 1) and (1 1 1) GaAs surfaces by a modified MBE method. MRS Internet Journal of Nitride Semiconductor Research, 1996, 1, 1.	1.0	6
219	A transmission electron microscopy investigation of SiC films grown on SiC substrates by solid-source molecular beam epitaxy. Journal of Materials Research, 1999, 14, 3226-3236.	2.6	5
220	Gross wellâ€width fluctuations in InGaN quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 1475-1481.	0.8	5
221	Atom probe extended to AlGaIn: three-dimensional imaging of a Mg-doped AlGaIn/GaN superlattice. Physica Status Solidi C: Current Topics in Solid State Physics, 2010, 7, 1781-1783.	0.8	5
222	Studies of efficiency droop in GaN based LEDs. Physica Status Solidi C: Current Topics in Solid State Physics, 2012, 9, 765-769.	0.8	5
223	Interfacial Structure and Chemistry of GaN on Ge(111). Physical Review Letters, 2013, 111, 256101.	7.8	5
224	Toward defectâ€free semiâ€polar GaN templates on preâ€structured sapphire. Physica Status Solidi (B): Basic Research, 2016, 253, 834-839.	1.5	5
225	Effect of QW growth temperature on the optical properties of blue and green InGaIn/GaN QW structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2016, 13, 209-213.	0.8	5
226	Structural and optical properties of (112̄...2) InGaIn quantum wells compared to (0001) and (112̄...0). Semiconductor Science and Technology, 2016, 31, 085007.	2.0	5
227	A study of the optical and polarisation properties of InGaIn/GaN multiple quantum wells grown on a-plane and m-plane GaN substrates. Science and Technology of Advanced Materials, 2016, 17, 736-743.	6.1	5
228	Xâ€ray reflectivity method for the characterization of InGaIn/GaN quantum well interface. Physica Status Solidi (B): Basic Research, 2017, 254, 1600664.	1.5	5
229	Insight into the impact of atomic- and nano-scale indium distributions on the optical properties of InGaIn/GaN quantum well structures grown on m-plane freestanding GaN substrates. Journal of Applied Physics, 2019, 125, 225704.	2.5	5
230	Optical properties of c-Plane InGaIn/GaN single quantum wells as a function of total electric field strength. Japanese Journal of Applied Physics, 2019, 58, SCCB09.	1.5	5
231	Performance and degradation characteristics of blueâ€violet laser diodes grown by molecular beam epitaxy. Physica Status Solidi (A) Applications and Materials Science, 2009, 206, 1205-1210.	1.8	4
232	Recombination mechanisms in heteroepitaxial non-polar InGaIn/GaN quantum wells. Journal of Applied Physics, 2012, 112, .	2.5	4
233	On the origin of blue-green emission from heteroepitaxial nonpolar a-plane InGaIn quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2012, 9, 465-468.	0.8	4
234	Combined electrical and resonant optical excitation characterization of multi-quantum well InGaIn-based light-emitting diodes. AIP Advances, 2016, 6, 075108.	1.3	4

#	ARTICLE	IF	CITATIONS
235	Au-free recessed Ohmic contacts to AlGaIn/GaN high electron mobility transistor: Study of etch chemistry and metal scheme. Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics, 2020, 38, 032207.	1.2	4
236	X-ray characterisation of the basal stacking fault densities of (112̄,2) GaN. CrystEngComm, 2021, 23, 6059-6069.	2.6	4
237	High-resolution electron microscopy study of the junction between a coherent {111} and an incoherent {121} twin boundary in TiAl. Philosophical Magazine A: Physics of Condensed Matter, Structure, Defects and Mechanical Properties, 1996, 73, 1647-1661.	0.6	3
238	A Combined Tem/Rheed, Sem/CI Study Of Epitaxial Gan. Materials Research Society Symposia Proceedings, 1997, 482, 458.	0.1	3
239	Local Electronic Structure Of Defects In Gan From Spatially Resolved Electron Energy-Loss Spectroscopy. Materials Research Society Symposia Proceedings, 1997, 482, 784.	0.1	3
240	Structure and Climb of Faulted Dipoles in GaAs. Physica Status Solidi A, 1999, 171, 53-57.	1.7	3
241	Reduction of Threading Dislocations in GaN grown on SiC plane sapphire by MOVPE. Materials Research Society Symposia Proceedings, 2004, 831, 678.	0.1	3
242	The mean inner potential of GaN measured from nanowires using off-axis electron holography. Materials Research Society Symposia Proceedings, 2005, 892, 184.	0.1	3
243	High resolution Laplace deep level transient spectroscopy studies of electron and hole traps in n-type GaN. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 1482-1484.	0.8	3
244	Structural features in GaN grown on a Ge(111) substrate. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 1802-1804.	0.8	3
245	A Direct Method for Charge Collection Probability Computation Using the Reciprocity Theorem. IEEE Transactions on Electron Devices, 2010, 57, 2455-2461.	3.0	3
246	Response to "Comment on 'The effects of Si doping on dislocation movement and tensile stress in GaN films'". J. Appl. Phys. 109, 073509 (2011)]. Journal of Applied Physics, 2011, 110, 096102.	2.5	3
247	Carrier capture efficiency in InGaIn/GaN LEDs: Role of high temperature annealing. AIP Conference Proceedings, 2014, , .	0.4	3
248	Difference in linear polarization of biaxially strained $I_n x n_x G a$	3.2	3
249	A study of the impact of in-situ argon plasma treatment before atomic layer deposition of Al ₂ O ₃ on GaN based metal oxide semiconductor capacitor. Microelectronic Engineering, 2015, 147, 277-280.	2.4	3
250	Electron-beam-induced damage in amorphous SiO ₂ and the direct fabrication of silicon nanostructures. Philosophical Magazine A: Physics of Condensed Matter, Structure, Defects and Mechanical Properties, 1998, 78, 491-506.	0.6	3
251	State of British science. Nature, 1991, 351, 513-513.	27.8	2
252	The effect of a Mg-doped GaN cap layer on the optical properties of InGaIn/AlGaIn multiple quantum well structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 2005-2008.	0.8	2

#	ARTICLE	IF	CITATIONS
253	Study of Defects in p-type Layers in III-nitride Laser Diode Structures Grown by Molecular Beam Epitaxy. Materials Research Society Symposia Proceedings, 2006, 955, 1.	0.1	2
254	Non-linear excitation and correlation studies of single InGaN quantum dots. Physica Status Solidi C: Current Topics in Solid State Physics, 2009, 6, 864-867.	0.8	2
255	Optical polarisation anisotropy in α -plane GaN/AlGaIn multiple quantum well structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2009, 6, S523.	0.8	2
256	Microscopic, electrical and optical studies on InGaN/GaN quantum wells based LED devices. , 2014, , .		2
257	Dynamics of carrier redistribution processes in InGaN/GaN quantum well structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2014, 11, 738-741.	0.8	2
258	High excitation density recombination dynamics in InGaN/GaN quantum well structures in the droop regime. Physica Status Solidi C: Current Topics in Solid State Physics, 2014, 11, 694-697.	0.8	2
259	Nanoscale structural and chemical analysis of F-implanted enhancement-mode InAlN/GaN heterostructure field effect transistors. Journal of Applied Physics, 2018, 123, 024902.	2.5	2
260	A Novel Technique to Investigate the Role of Traps in the Off-state Performance of AlGaIn/GaN High Electron Mobility Transistor on Si Using Substrate Bias. Physica Status Solidi (A) Applications and Materials Science, 2020, 217, 1900794.	1.8	2
261	The Puzzle of Exciton Localisation in GaN-Based Structures: TEM, AFM and 3D APFIM Hold the Key. Springer Proceedings in Physics, 2008, , 3-12.	0.2	2
262	Dual barrier InAlN/AlGaIn/GaN-on-silicon high-electron-mobility transistors with Pt- and Ni-based gate stacks. Physica Status Solidi (A) Applications and Materials Science, 2017, 214, 1600835.	1.8	2
263	Graphene on silicon: Effects of the silicon surface orientation on the work function and carrier density of graphene. Physical Review B, 2022, 105, .	3.2	2
264	Crucifixion date. Nature, 1990, 348, 684-684.	27.8	1
265	Control of Point Defects in Semiconductors. Materials Research Society Symposia Proceedings, 1994, 373, 529.	0.1	1
266	EELS Studies of B2-Type Transition Metal Aluminides: Experiment and Theory. Materials Research Society Symposia Proceedings, 1995, 408, 567.	0.1	1
267	Atom positions in the R-phase unit cell in TiNi shape memory alloy. Journal of Materials Science, 1996, 31, 4227-4231.	3.7	1
268	Interfaces and Defects in Opto-Electronic Semiconductor Films Studied by Atomic Resolution STEM. Microscopy and Microanalysis, 1997, 3, 461-462.	0.4	1
269	Energy-Filtered Transmission Electron Microscopy of Multilayers in Semiconductors. Materials Research Society Symposia Proceedings, 1998, 523, 159.	0.1	1
270	Electron Microscopy, Electrical Activity, Artefacts and the Assessment of Semiconductor Epitaxial Growth. Materials Research Society Symposia Proceedings, 1998, 523, 207.	0.1	1

#	ARTICLE	IF	CITATIONS
271	Electronic and Structural Properties of Partially Crystallized Silicon Produced by Solid-Phase Crystallization of As-Deposited Amorphous Silicon. Journal of the Electrochemical Society, 1999, 146, 306-312.	2.9	1
272	Characterisation of Epitaxial Laterally Overgrown Gallium Nitride Using Transmission Electron Microscopy. Physica Status Solidi (B): Basic Research, 1999, 216, 633-637.	1.5	1
273	Analysis of InGaN-GaN quantum well chemistry and interfaces by transmission electron microscopy and X-ray scattering. Materials Research Society Symposia Proceedings, 2003, 798, 524.	0.1	1
274	Growth of Uncracked Al _{0.80} Ga _{0.20} N/GaN DBR on Si(111). Materials Research Society Symposia Proceedings, 2004, 831, 377.	0.1	1
275	Temperature current-voltage characterisation of MOCVD grown InGaN/GaN MQW LEDs. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 2145-2148.	0.8	1
276	Resonant photoluminescence excitation studies of InGaN/GaN single quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 2001-2004.	0.8	1
277	Progress in MOVPE growth of crack-free AlGaN based Bragg reflectors on Si(111). Physica Status Solidi (A) Applications and Materials Science, 2006, 203, 1618-1621.	1.8	1
278	High brightness near-ultraviolet resonant LEDs. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 2056-2058.	0.8	1
279	Assessment of scanning spreading resistance microscopy for application to n-type GaN. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 1652-1654.	0.8	1
280	Origin of additional threading dislocations in AlGaN grown on GaN using AlN as an interlayer. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 1743-1745.	0.8	1
281	Impact of thermal treatment on the optical performance of InGaN/GaN light emitting diodes. AIP Advances, 2015, 5, 107121.	1.3	1
282	Molecular beam epitaxy of free-standing bulk wurtzite Al _x Ga _{1-x} N layers using a highly efficient RF plasma source. Physica Status Solidi C: Current Topics in Solid State Physics, 2016, 13, 217-220.	0.8	1
283	Modelling the closely-coupled cascode switching process. , 2016, , .		1
284	Investigating efficiency droop in InGaN/GaN quantum well structures using ultrafast time-resolved terahertz and photoluminescence spectroscopy. Physica Status Solidi C: Current Topics in Solid State Physics, 2016, 13, 252-255.	0.8	1
285	Effect of electron blocking layers on the conduction and valence band profiles of InGaN/GaN LEDs. Physica Status Solidi C: Current Topics in Solid State Physics, 2016, 13, 262-265.	0.8	1
286	Perspectives on Electronic and Photonic Materials. Springer Handbooks, 2017, , 1-1.	0.6	1
287	Alloy fluctuations at dislocations in III-nitrides: identification and impact on optical properties. , 2018, , .		1
288	Microstructure and Strain-Free Lattice Parameters of ScGaN Films. Materials Research Society Symposia Proceedings, 2005, 892, 656.	0.1	1

#	ARTICLE	IF	CITATIONS
289	Electron Energy Loss Spectroscopy (EELS) of GaN Alloys and Quantum Wells. Microscopy and Microanalysis, 2001, 7, 1182-1183.	0.4	1
290	Evolution and religion. Nature, 1993, 366, 296-296.	27.8	0
291	Stebic Revisited. Materials Research Society Symposia Proceedings, 1994, 354, 425.	0.1	0
292	An Hrem Investigation of a {121}L10 Boundary in Tial. Materials Research Society Symposia Proceedings, 1994, 364, 605.	0.1	0
293	The Economic Laws of Scientific Research Terence Kealey Macmillan Press, Basingstoke and London, 1996 (382 pages). £47.50, hardback, ISBN 0-333-56045-0; £15.99, paperback, ISBN 0-333-65755-1. Also St Martin's Press, New York, 1996, ISBN 0-312-12847-9.. European Review, 1997, 5, 443.	0.7	0
294	Electronic Structure, Charge Transfer and Bonding in Intermetallics Using EELS and Density Functional Theory. Materials Research Society Symposia Proceedings, 1998, 552, 1.	0.1	0
295	The Effect of the Buffer Layer on the Structure, Mobility and Photoluminescence of MBE grown GaN. Materials Research Society Symposia Proceedings, 1999, 595, 1.	0.1	0
296	The Effect of Local Symmetry on Atomic Resolution EELS Near-Edge Structures: Predictions for Grain Boundaries In NiAl. Microscopy and Microanalysis, 2000, 6, 186-187.	0.4	0
297	Atomic Site Occupancy of Platinum Group Metals in the $\hat{\Gamma}^{\text{TM}}$ (L12) Phase of a $\hat{\Gamma}^{\text{TM}}$ Complex Nickel Base Superalloy Using Alchemi (Atomic Location by Channelling Enhanced Microanalysis). Microscopy and Microanalysis, 2001, 7, 346-347.	0.4	0
298	Crystallization transformations in vacuum-deposited amorphous aluminum fluoride self-developing thin-film resists induced by electron-beam irradiation. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 2002, 20, 986-990.	2.1	0
299	Energy filtered imaging in a FEG-SEM for enhanced dopant contrast. Microscopy and Microanalysis, 2002, 8, 718-719.	0.4	0
300	The effect of AlGaIn and SiN interlayers on GaN/Si(111). Physica Status Solidi C: Current Topics in Solid State Physics, 2005, 2, 956-959.	0.8	0
301	The effect of Si on the growth mode of GaN. Physica Status Solidi C: Current Topics in Solid State Physics, 2006, 3, 1570-1574.	0.8	0
302	Growth and characterization of semi-polar (11-22) GaN with in-situ SiNx interlayers. Materials Research Society Symposia Proceedings, 2006, 955, 1.	0.1	0
303	Resonant Photoluminescence Spectroscopy of InGaIn/GaN Single Quantum Well Structures. AIP Conference Proceedings, 2007, , .	0.4	0
304	Palladium-based on-wafer electroluminescence studies of GaN-based LED structures. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 2219-2221.	0.8	0
305	Effects of resonant LO phonon assisted excitation on the photoluminescence spectra of InGaIn/GaN quantum wells. Physica Status Solidi C: Current Topics in Solid State Physics, 2008, 5, 2270-2273.	0.8	0
306	High resolution Laplace Deep Level Transient Spectroscopy studies of shallow and deep levels in n-GaN. Optoelectronic and Microelectronic Materials and Devices (COMMAD), Conference on, 2008, , .	0.0	0

#	ARTICLE	IF	CITATIONS
307	Q-factor measurements on planar nitride cavities. Physica Status Solidi C: Current Topics in Solid State Physics, 2010, 7, 1866-1868.	0.8	0
308	Characteristics and applications of InGaN micro-light emitting diodes on Si substrates. , 2013, , .		0
309	Precision transfer printing of ultra-thin AlInGaN micron-size light-emitting diodes. , 2013, , .		0
310	How Cutting-Edge Atomic Resolution Microscopy Can Help to Solve Some of the World's Energy Problems. Microscopy and Microanalysis, 2014, 20, 11-14.	0.4	0
311	How Cutting-Edge Atomic Resolution Microscopy Can Help to Solve Some of the World's Energy Problems. Microscopy and Microanalysis, 2014, 20, xcvi-c.	0.4	0
312	Terahertz magnetospectroscopy studies of an AlGaIn/GaN heterostructure. , 2016, , .		0
313	Toward defect-free semi-polar GaN templates on pre-structured sapphire (Phys. Status Solidi B 5/2016). Physica Status Solidi (B): Basic Research, 2016, 253, 1024-1024.	1.5	0
314	Atomic Resolution Imaging of Dislocations in AlGaIn and the Efficiency of UV LEDs. Microscopy and Microanalysis, 2018, 24, 4-5.	0.4	0
315	A TEM Investigation of Crack Reduction in AlGaIn/GaN Heterostructures Using an AlN Interlayer. Materials Research Society Symposia Proceedings, 2005, 892, 632.	0.1	0
316	Significant interlayer coupling in bilayer graphene and double-walled carbon nanotubes: A refinement of obtaining strain in low-dimensional materials. Physical Review B, 2022, 105, .	3.2	0
317	Wafer-scale Graphene Anodes Replace Indium Tin Oxide in Organic Light-Emitting Diodes (Advanced) Tj ETQq1, 1.0.784314 rgBT /Ov	1.7	0